

Supporting Information

High-performance stretchable photodetector based on epitaxial CdTe ultrathin films

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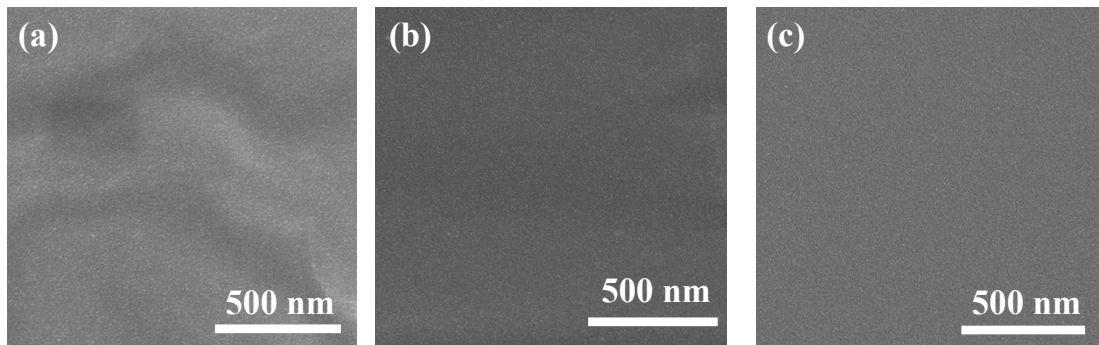


Fig. S1. Top-view SEM images of the transferred CdTe films on PDMS under a strain of (a) 0%, (b) 15.0%, (c) 35.0%.

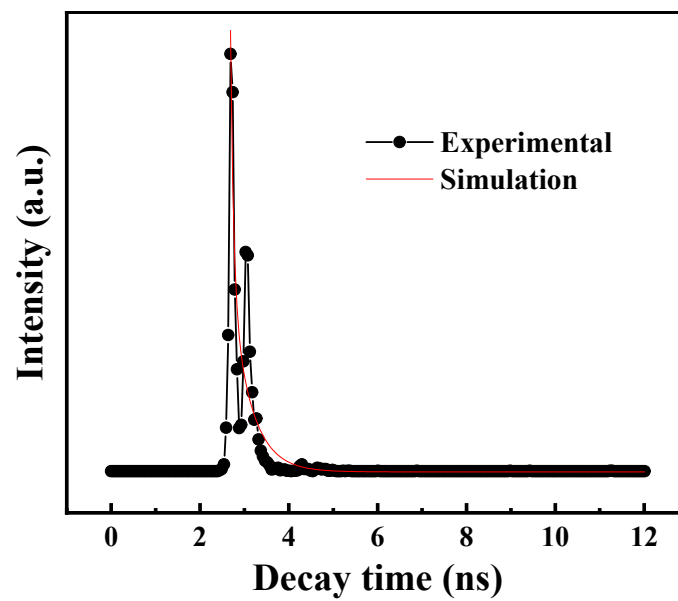


Fig. S2. Time-resolved PL decay curve of the CdTe film. The red line is the double exponential fit.

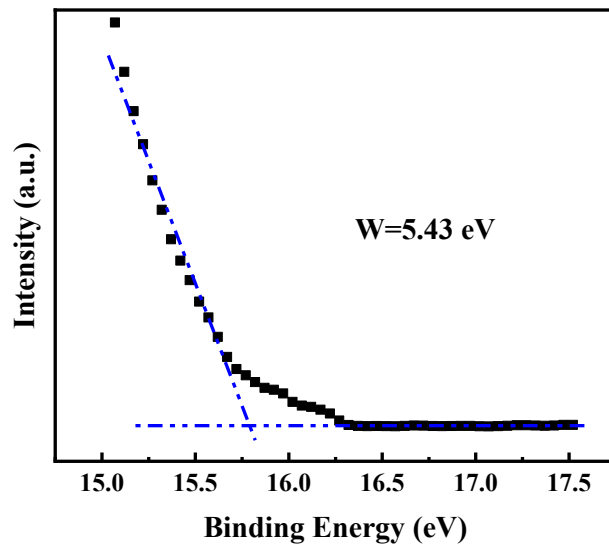


Fig. S3. UPS spectra of the CdTe film. The value at the junction of the horizontal line and the extension line is the cutoff of the highest binding energy.